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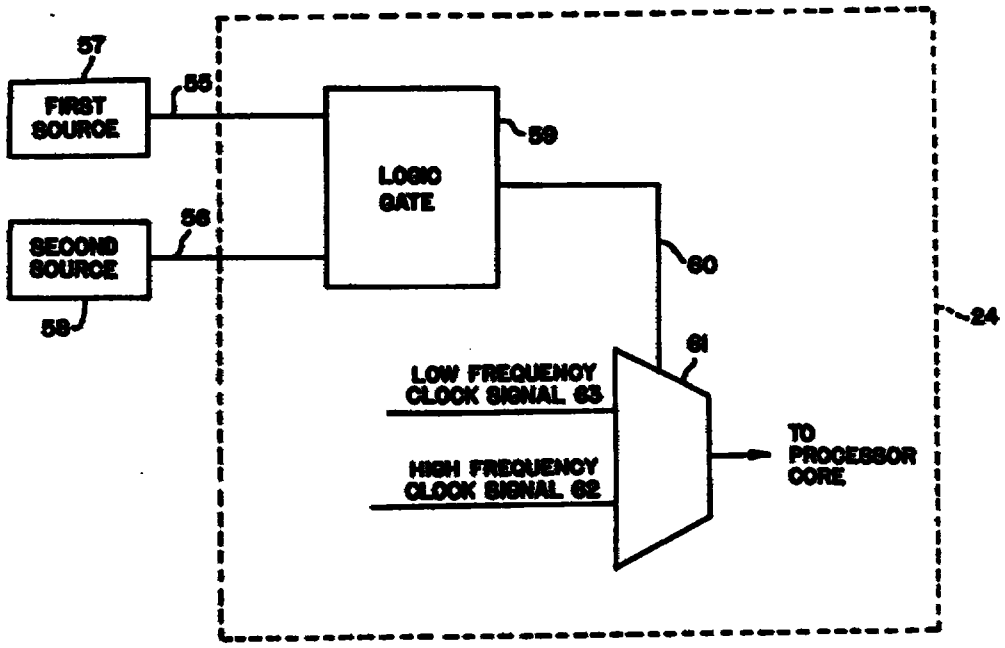
(54) Title: EMPLOYING ON DIE TEMPERATURE SENSORS AND FAN-HEATSINK FAILURE SIGNALS TO CONTROL POWER DISSIPATION




(57) Abstract

A circuit (24) and method for reducing an internal clocking frequency (62, 63) of the semiconductor device upon receiving a first signal (55) indicating a fan element disposed on the semiconductor device is operating at an unacceptable performance level and/or a second signal (56) indicating that the semiconductor device is operating at a temperature greater than a prescribed boundary temperature.

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